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|-----------------------------------|--|--|-------------------------|--|------------------|
| Notice of References Cited | | | Application/Control No. | Applicant(s)/Patent Under Reexamination 10/565,949 WEISS ET AL. | |
| | | | Examiner | Art Unit Hai H. Huynh | 3747 Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|--------------------|----------------|
| * | A | US-6,178,943 B1 | 01-2001 | Taga et al. | 123/295 |
| * | B | US-6,557,524 B2 | 05-2003 | Tsunooka, Takashi | 123/399 |
| * | C | US-6,708,668 B2 | 03-2004 | Yoshida et al. | 123/295 |
| * | D | US-7,007,462 B2 | 03-2006 | Kitahara, Yasuhisa | 60/285 |
| * | E | US-7,013,637 B2 | 03-2006 | Yoshida, Iwao | 60/285 |
| * | F | US-2005/0039444 A1 | 02-2005 | Nishizawa et al. | 060/285 |
| * | G | US-2007/0055436 A1 | 03-2007 | Weiss et al. | 701/101 |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|---------------|----------------|
| | N | JP 2001-152835 | 06-2001 | Japan | | F01N-3/20 |
| | O | JP 2003-27998 | 01-2003 | Japan | Yoshida et al | F02D-43/00 |
| | P | JP 2006-9704 | 01-2006 | Japan | Takagi et al | F02D-41/04 |
| | Q | JP 2006-16973 | 01-2006 | Japan | Takagi et al | F02D-41/04 |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| | | |
|---|---|---|
| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
| | U | |
| | V | |
| | W | |
| | X | |

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